## Docket No.: 50090-443

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :

a / Puel. and

Kazunobu MIKI

E. Willia 2-19-03

Serial No.:

Group Art Unit: ,

Filed: October 10, 2001

Examiner:

For:

SEMICONDUCTOR ELEMENT TEST APPARATUS, AND METHOD OF TESTING

SEMICONDUCTOR ELEMENT USING THE APPARATUS

## PRELIMINARY AMENDMENT

Commissioner for Patents Washington, DC 20231

Sir:

Prior to examination of the above-referenced application, please amend the application as

follows:

IN THE DRAWINGS:

On Page 8 in the "Brief Description of the Drawings", please add the following:

AIE

--Fig. 19A and 19B are typical views showing a round-head screw.--

## **REMARKS**

The above application is amended to include Figures 19A and 19B in the "Brief Description of the Drawings". Attached hereto is a clean copy of page 8 as amended. Entry of this preliminary amendment is respectfully requested.

Respectfully submitted,

MCDERMOTT, WILL & EMERY

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